INTRODUCTION

With the increase in commercial applications of microwave and radio frequency (RF) equipment, designers have placed a greater demand on consistent performance and low price. The receiver front end described in this paper utilizes low-cost, off-the-shelf technology from NEC/California Eastern Labs to produce a circuit which can be used in many commercial designs.

The starting point for this circuit was the UPC2721GR MMIC down converter. This device includes a mixer with an internal local oscillator (LO) and an intermediate frequency (IF) buffer amplifier on a single MMIC chip. The internal LO is tuned using an external varactor diode. The UPC2721GR also allows the option of using an external oscillator.

In order to achieve an improved noise figure for the circuit, a low noise amplifier (LNA) was added at the RF input to the down converter. The LNA was designed using a discrete low noise GaAs MESFET (NE76038) with a matching structure made using discrete components. The NE76038 is fabricated using ion implantation techniques to improve RF and DC performance, and features a recessed 0.3 micron gate and triple epitaxial technology. Typical noise figures of 1.8 dB can be obtained at 12 GHz, with 7.5 dB associated gain, even in the low cost plastic “38” package. The device is also available in ceramic packages and in chip form.

A low-pass filter was placed after the down converter to reduce the LO and RF power at the output, and an MMIC buffer amplifier (UPC2710T) was included at the end of the chain to increase the overall system gain. The UPC2710T features 33 dB typical gain up to 1500 MHz in an inexpensive six-pin minimold plastic package. A block diagram of the entire system is shown in Figure 1.
Both the MMIC parts used in this design are manufactured using the NESAT III MMIC process developed by NEC. The process features include:

- A low-energy, boron-ion base implant which reduces base transit times
- A 0.6—µm emitter line width which results in low base resistance and low parasitic capacitances.
- An arsenic ion-implanted buried layer and thin epitaxial layer to reduce collector resistance.
- Arsenic ion-implanted poly-silicon resistors on a thick SiO₂ layer to reduce parasitic capacitances of the on-chip resistors.
- PtSi/Ti/Pt/Au metallization and reactive ion etching to permit reliable production of 1-µm electrode lines and gaps.
- A silicon nitride passivation layer for scratch and contamination protection.

These process features result in reliable and reproducible silicon MMICs with cutoff frequencies (fT) approaching 20 GHz.

TARGET SPECIFICATIONS

The design goal for this circuit was to produce a low-noise, high-gain receiver front-end. Operating frequency was to be 1800 MHz at the RF input, with a 1700 MHz LO resulting in a 100 MHz IF at the output. A further design goal was that the active parts used should be low cost: less than $10 (based on 10K piece quantities). The design specs were as follows:

<table>
<thead>
<tr>
<th>Parameter</th>
<th>LN Amp</th>
<th>Mixer</th>
<th>Filter</th>
<th>IF Amp</th>
<th>Overall</th>
</tr>
</thead>
<tbody>
<tr>
<td>Gain (dB)</td>
<td>14</td>
<td>20</td>
<td>-6</td>
<td>32</td>
<td>60</td>
</tr>
<tr>
<td>Noise Figure (dB)</td>
<td>1</td>
<td>11</td>
<td>6</td>
<td>3.5</td>
<td>2.5</td>
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<tr>
<td>Saturation Power (dBm)</td>
<td>2</td>
<td>5</td>
<td>-</td>
<td>13</td>
<td>13</td>
</tr>
<tr>
<td>Input Return Loss (dB)</td>
<td>10</td>
<td>-</td>
<td>15</td>
<td>6</td>
<td>10</td>
</tr>
<tr>
<td>Output Return Loss (dB)</td>
<td>8</td>
<td>-</td>
<td>15</td>
<td>12</td>
<td>12</td>
</tr>
<tr>
<td>Cost ($ @ 10K pc)**</td>
<td>$2.10</td>
<td>$2.00</td>
<td>-</td>
<td>$1.70</td>
<td>$5.70</td>
</tr>
</tbody>
</table>

* LNA specs at 1800 MHz
** Cost of active parts only

DESIGN APPROACH

Since the MMIC portions of this circuit are fixed in their performance, the design focused on the low noise amplifier. The NE76038 GaAs FET was chosen for its low noise figure, high reliability and low cost. The device was modeled using CAD (Touchstone) and the matching structure was optimized for a 100 MHz bandwidth centered at 1800 MHz. Discrete tuning elements were used with the goal of minimizing noise figure, while maintaining reasonable gain and return loss. The predicted circuit performance was 1.02 dB noise figure with 15.7 dB gain at 1800 MHz. Input and output return loss were predicted to be -9.9 dB and -8.3 dB respectively.

A test circuit for the low noise amplifier was assembled and tested separately from the other components of the receiver. This was done so that the tuning elements could be optimized for minimum noise figure. The test circuit layout with the final values of the tuning elements is shown in Figure 2. 1800 MHz test results obtained from the final circuit were:

Small Signal Gain: 15.2 dB  Noise Figure: 0.6 dB
Input Return Loss: 5.2 dB  Output Return Loss: 3.5 dB

The next stage of the design was to test the low noise amplifier breadboard with the other components of the system. To accomplish this, separate test fixtures were built for each of the components in the chain. Test results on circuits for the down converter and the IF buffer amplifier were:

Down Converter: UPC2721GR
RF = 1800 MHz, LO = 1700 MHz
IF = 100 MHz
Conversion Gain: 19.5 dB

IF Amp: UPC2710T
Small Signal Gain: 33.5 dB
Input Return Loss: 9.8 dB
Output Return Loss: 14.0 dB
The low pass filter test circuit was adjusted to reduce the LO and RF power level at the output to 10 dB below the IF signal level. At this time it became apparent that even though the filter had been designed to be somewhat lossy, the oscillator power being reflected back into the mixer of the UPC2721GR was causing an unacceptable level of spurious signals. A 3 dB pad was inserted between the filter and the mixer of the UPC2721GR, and this minimized the spur problem. The small signal gain of this line-up was 59.8 dB - close enough to the design goal to go to a final layout.

**FINAL LAYOUT**

The final circuit layout is shown in Figure 3. The pad between the mixer and the filter was increased to 6 dB in the final design to further improve the spur performance at the output. The circuit was etched on 10 mil thick, Duroid 5880 substrate. Outside dimensions are 1.8 by 1.25 inches. The gain and noise figure performance of the final circuit versus input frequency are shown in Figure 4. In addition, the following data was taken:

- Input Return Loss (1800 MHz): 6.0 dB
- Output Return Loss (100 MHz): 14.2 dB
- Power (1 dB compressed gain): 11.2 dBm

**CONCLUSION**

The drive to reduce costs for commercial RF and microwave products does not mean that performance must be sacrificed. Low-cost, off-the-shelf discrete and MMIC parts from NEC/California Eastern Labs can be used to provide reliable circuits which deliver top shelf performance for commercial applications.

**ADDENDUM**

After submission of this paper to the January, 1993 Wireless Symposium, some additional testing was performed. Specifically, the low noise amplifier on the individual test fixture was retuned for operation at 900 MHz. The external load matching components were revised to the values shown in Figure 5. This test fixture was then combined with the existing mixer, filter and IF amplifier fixtures with the results shown on Figure 6. Because the internal oscillator of the mixer had been designed for operation at 1700 MHz, the minimum LO frequency obtainable was 1170 MHz. Noise figure of the combined circuit was measured as 2.4 dB at an RF frequency of 970 MHz, and IF frequency of 200 MHz. Better results can be expected from a circuit designed from scratch for 900 MHz operation.
Figure 4. Gain & Noise Figure (Local Oscillator: 1700 MHz).

Figure 5. NE76038 Low Noise Amp Layout.

Figure 6. Modified Circuit Gain & Noise Figure (Local Oscillator: 1170 MHz)

PART LIST

1. 100 pF Chip Capacitor
2. 2.7 pF Chip Capacitor
3. L1: 0.095, 0.020, 5T (inch)
4. NE76038
5. 68 pF Chip Capacitor
6. L2: 0.6 nH Microstrip Line, 0.1 length and 0.01 width.
7. 220 nH Chip Inductor
8. 10000 pF Chip Inductor